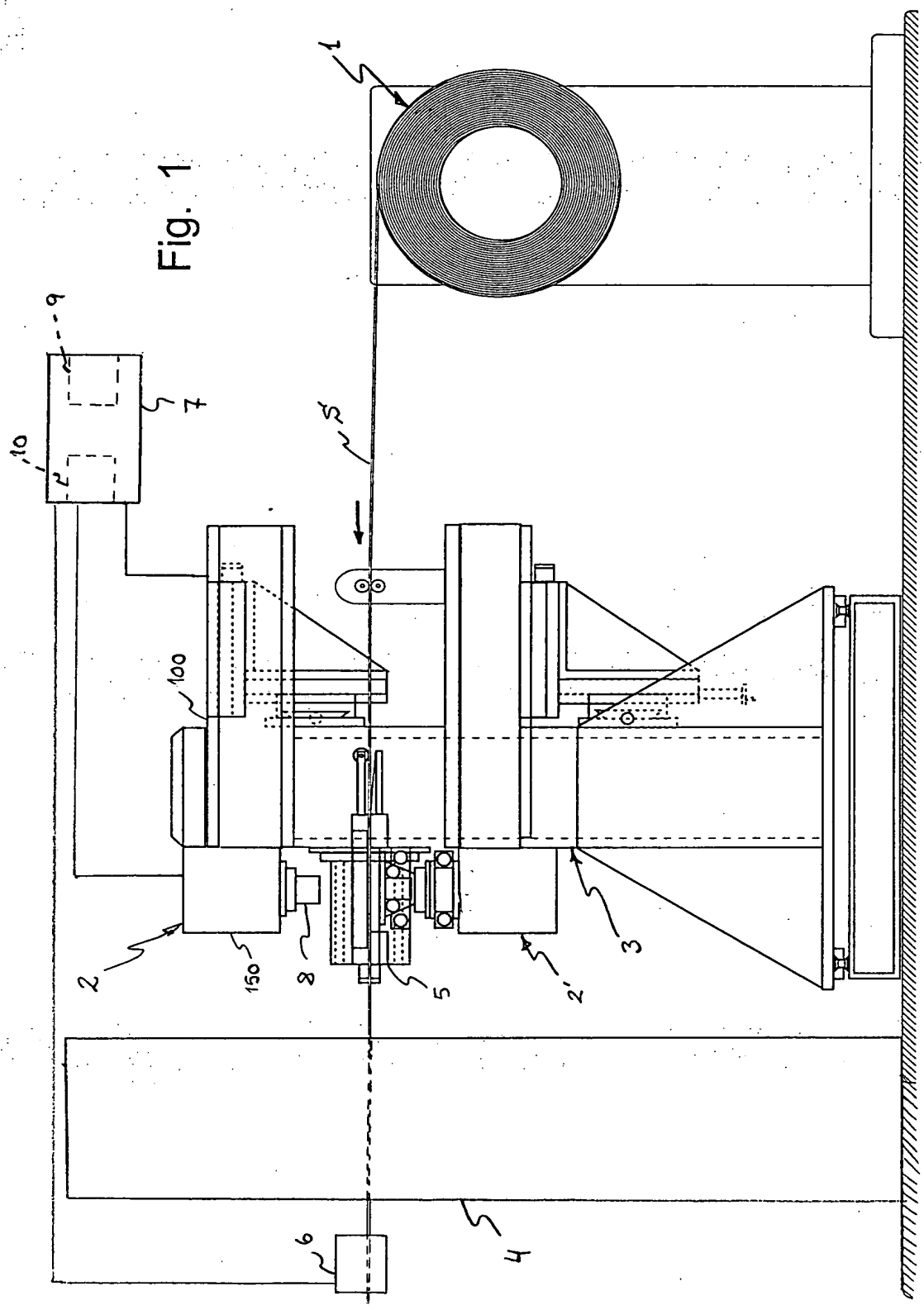


FIG. 1 is a schematic diagram of a system for measuring the thickness of a material. The system includes a material 1, a sensor 2, a sensor 2', a sensor 3, a sensor 4, a sensor 5, a sensor 6, a sensor 7, a sensor 8, a sensor 9, and a sensor 10. The sensors are arranged in a line, and the material 1 is positioned between the sensors. The sensors are connected to a central processing unit 100, which is connected to a display 150. The display 150 shows the thickness of the material 1. The system is mounted on a base 4, and the sensors are mounted on a frame 5. The frame 5 is connected to the base 4 by a hinge 6. The frame 5 is also connected to the sensors 2, 2', 3, 4, 5, 6, 7, 8, 9, and 10. The sensors 2, 2', 3, 4, 5, 6, 7, 8, 9, and 10 are arranged in a line, and the material 1 is positioned between the sensors. The sensors are connected to a central processing unit 100, which is connected to a display 150. The display 150 shows the thickness of the material 1.

Fig. 1



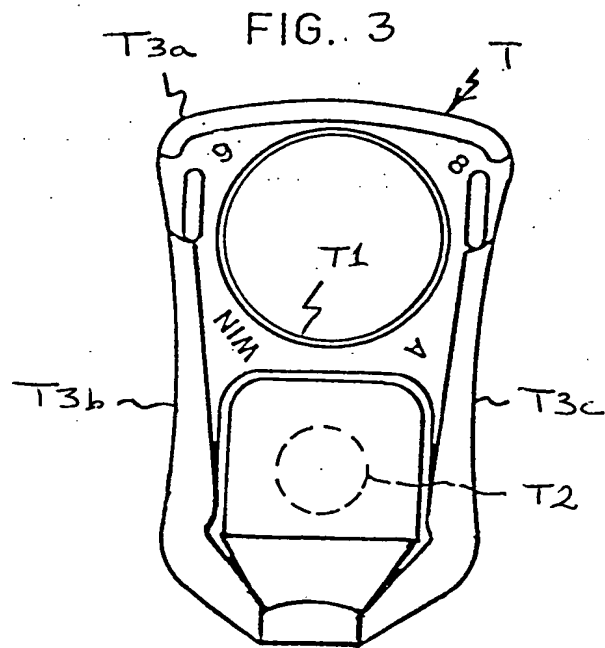
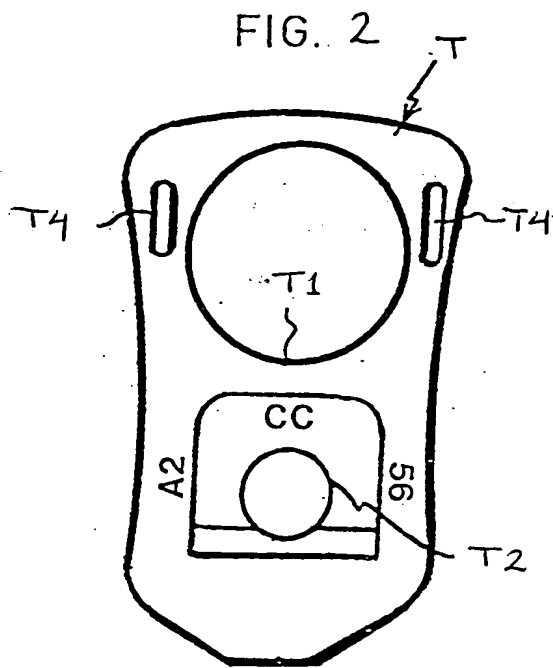


FIG. 4

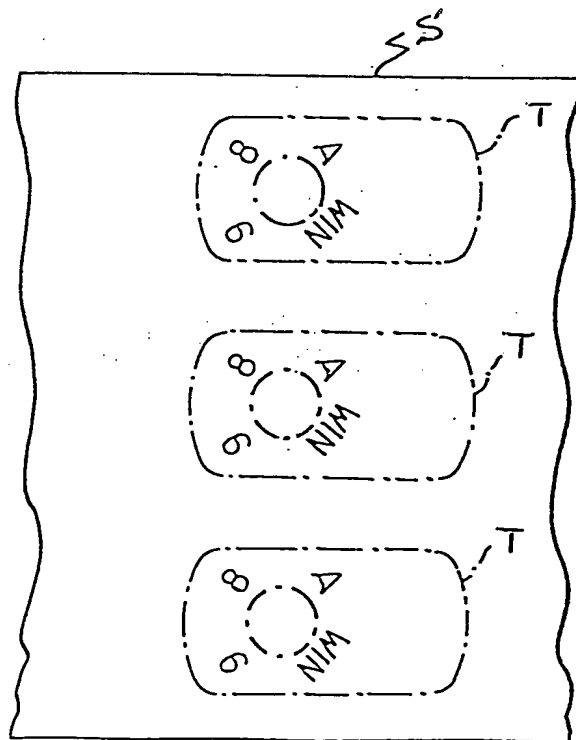


FIG. 5

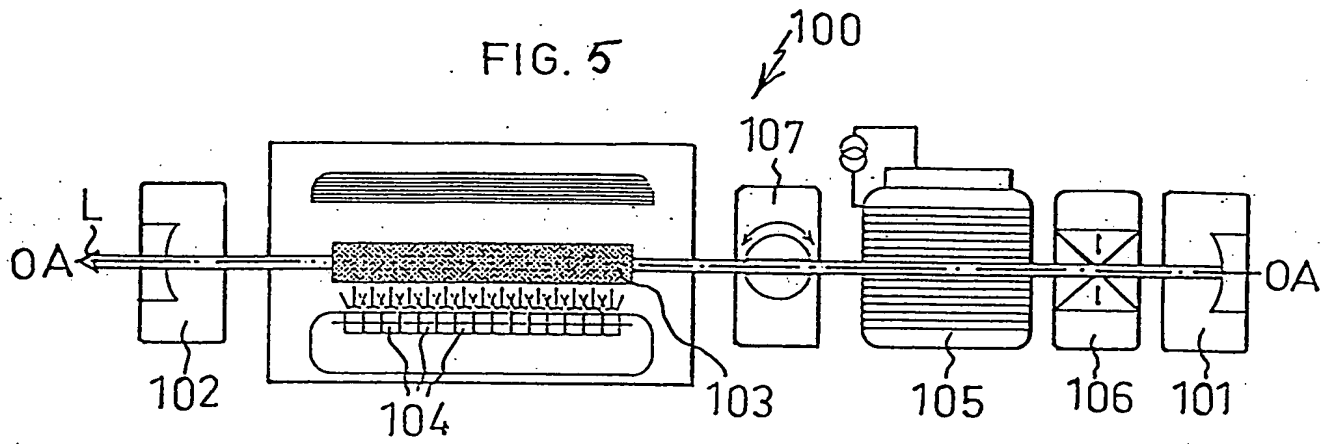


FIG. 6

